

Title (en)
METHOD AND APPARATUS FOR MEASURING A PARAMETER OF INTEREST USING IMAGE PLANE DETECTION TECHNIQUES

Title (de)
VERFAHREN UND VORRICHTUNG ZUM MESSEN EINES INTERESSIERENDEN PARAMETERS MIT BILDEBENENERFASSUNGSTECHNIKEN

Title (fr)
PROCÉDÉ ET APPAREIL PERMETTANT DE MESURER UN PARAMÈTRE D'INTÉRÊT AU MOYEN DE TECHNIQUES DE DÉTECTION DE PLAN D'IMAGE

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Application
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Abstract (en)
A inspection apparatus, method, and system associated therewith are described herein. In a non-limiting embodiment, a inspection apparatus includes an optical system and an imaging system. The optical system may be configured to output an illumination beam incident on a target including one or more features, and the illumination beam being polarized with a first polarization when incident on the target. The imaging system may be configured to obtain intensity data representing at least a portion of the illumination beam scattered by the one or more features, where the portion of the illumination beam has a second polarization orthogonal to the first polarization; generate image data representing an image of each of the feature(s) based on the intensity data; and determine a measurement of a parameter of interest associated with the feature(s) based on an amount of the portion of the illumination beam having the second polarization.

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Citation (applicant)

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